



250	307	Subclass
250	Class	ISSUE CLASSIFICATION

## BEST AVAILABLE COPY

PATENT NUMBER

## U.S. UTILITY Patent Application

O.I.P.E.	PATENT DATE
KS SCANNED 11/17/04 G.A. (3)	11/17/04

APPLICATION NO.	CONT/PRIOR	CLASS	SUBCLASS	ART UNIT	EXAMINER
09/871739	F	250	307	2878-2853	Mount

APPLICANTS

Hiromi Inada  
Isao Nagaoki  
Hiroyuki Kobayashi

TITLE

Method and device for observing a specimen in a field of view of an electron microscope

PTO-2040  
12/99

## ISSUING CLASSIFICATION

ORIGINAL		CROSS REFERENCE(S)			
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)		
250	307	250	311		
INTERNATIONAL CLASSIFICATION					
601 N 23100					
<input type="checkbox"/> Continued on Issue Slip Inside File-Jacket					

 TERMINAL DISCLAIMER

The term of this patent has been disclaimed.

The term of this patent does not extend beyond the term of U.S Patent No. \_\_\_\_\_

The terminal date of this patent have been \_\_\_\_\_

## WARNING:

The information disclosed herein may be restricted. Unauthorized disclosure may be prohibited by the United States Code Title 35, Sections 122, 181 and 368. Possession outside the U.S. Patent & Trademark Office is restricted to authorized employees and contractors only.

Form PTO-438A  
(Rev. 8/99)

DRAWINGS			CLAIMS ALLOWED	
Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
16	24	1	36	1
NOTICE OF ALLOWANCE MAILED				
Bleu Mount 5/17/2004 (Assistant Examiner) (Date)				
6/01/04				
ISSUE FEE				
Amount Due			Date Paid	
1630.				
ISSUE BATCH NUMBER				
6/01/04				

FILED WITH:  DISK (CRF)  FICHE  CD-ROM  
(Attached in pocket on right inside flap)